

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	Giles et al.) Art Unit:	3642	
) Art Omt.	3042	
Serial Number:	10/603,824) Examiner:	N/A	
Filed:	June 26, 2003) Atty Docket:	DEH058	
For: Mass Spectro	ometer			
COMMISSIONER PO Box 1450 Alexandria, VA 22				
Sir:				
The below identified comr	nunication(s) or docume	nt(s) is(are) submitted in t	he above application or proceeding:	
Amendment/Response		☐ Issue Fee Transmittal		
Supplemental Informat	tion Disclosure	Check in the Amount	of \$	
Statement with 28 ref		Assignment		
		Associate Power of A	ttorney	
		075 for any deficiency or by the Deposit Account 1	surplus in connection with this communicatio	n. A

Everett G. Diederiks, Jr. Attorney for Applicant Registration Number: 33,323

Date: April 19, 2004

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For: Mass Spectrometer			
COMMISSIONER FOR PATENTS PO Box 1450 Alexandria, VA 22313-1450			
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 ☐ Amendment/Response ☑ Supplemental Information Disclosure Statement with 28 refs. ☐ 	☐ Issue Fee Transmittal ☐ Check in the Amount of ☐ Assignment ☐ Associate Power of Atto		
Please charge Deposit Account Number 04-10 duplicate copy of this sheet is provided for use			4

Respectfully-submitted,

Everett G. Diederiks, Jr. Attorney for Applicant Registration Number: 33,323

Date: April 19, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

n re Application of Giles et al.

Art Unit:

3642

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Examiner:

N/A

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For:

Mass Spectrometer

Commissioner for Patents PO Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to Rule 37 C.F.R. §1.51(b), §1.56, §1.97, and §1.98, this Information Disclosure Statement is submitted in the above-identified patent application. A listing of documents to be published on the face of any patent granted from this application is submitted herewith on Form PTO-1449 with a copy thereof.

CONCISE STATEMENT OF RELEVANCY (Non-English Language Documents Only)

Each of the foreign references cited in the Information Disclosure Statement generally pertains to the art of mass spectrometry. Abstracts in English are being provided to aid the Examiner in considering the potential relevancy of the cited documents.

CERTIFICATION

This Information Disclosure Statement is submitted within three months of the filing date of and/or prior to the issuance of a first Office Action in the above-identified U.S. patent application.

The Examiner is requested to acknowledge consideration of the information provided in this paper in accordance with prescribed procedures.

Respectfully submitted,

Everett G. Diederiks, Jr.

Attorney for Applicant

Registration No. 33,323

Date: April 19, 2004

ATTY DOCKET NO.	SERIAL NO.
DEH058	10/603,824
APPLICANT	
Giles et al.	
FILING DATE	GROUP
June 26, 2003	3642
	DEH058 APPLICANT Giles et al. FILING DATE

2004

U.S. Patent Documents

Examine EMAR	•/		U.S. Patent Documents			
Examine Initial	Document Number	Date	Patentee/Applicant	Class	Subclass	Filing Date if Appropriate
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Foreign Patent Documents

Examiner	Document Number	Publication	Country/Agency	Class	Subclass		slation
Initial		Date				Yes	No
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	11-307040	11/99	Japan				
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	2000-123780	04/00	Japan				
	2,375,653	11/02	UK				
	WO 94/01883	01/94	wo				

WO 97/49111	12/97	wo		
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 Other Documents (Including Author, 11the, Date, 1 cl thich I ages, 1 lace of 1 abheation, Etc.)
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Examiner	Date Considered

Examiner: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; Draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.